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Set Name	Query	Hit Count	Set Name
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<u>L12</u> l10 and l11		0	<u>L12</u>
<u>L11</u> spin\$4 or spun or counterspin\$4 or counterspun or (counter adj spun) or (counter adj spin\$4)		1792	<u>L11</u>
<u>L10</u> missile\$1 or rocket\$1 or projectile\$1		46	<u>L10</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI; PLUR=YES; OP=OR</i>			
<u>L9</u> l7 and nose\$1		39	<u>L9</u>
<u>L8</u> l4 and nose.ti,ab. and body.ti,ab.		18	<u>L8</u>
<u>L7</u> l4 and (section\$1 or portion\$1).ti,ab.		150	<u>L7</u>
<u>L6</u> l4 and l5		1	<u>L6</u>
<u>L5</u> counterspin\$4 or counterspun or (counter adj spun) or (counter adj spin\$4)		286	<u>L5</u>
<u>L4</u> (surface\$1 or canard\$1).ti,ab. and l3		400	<u>L4</u>
<u>L3</u> l1 and l2		1790	<u>L3</u>
<u>L2</u> (spin\$4 or spun or counterspin\$4 or counterspun).ti,ab.		345001	<u>L2</u>
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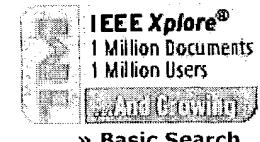
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- Basic
- Advanced

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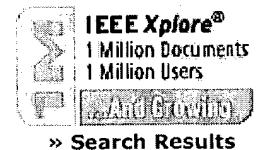
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Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)

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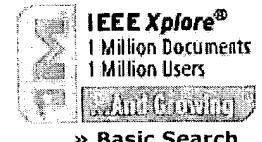


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Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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And

In:

And

In:

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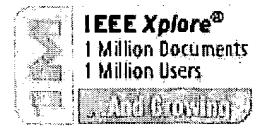
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

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- Basic
- Advanced

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- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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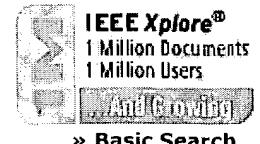
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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 And

 In:
 And

 In:

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- [Home](#)
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Tables of Contents

- [Journals & Magazines](#)
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- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)

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- [Join IEEE](#)
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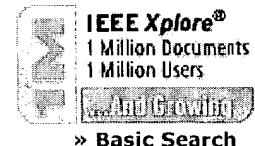
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- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Establish IEEE Web Account
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projectile In: All Fields

And

canard In: All Fields

And

counterspun In: All Fields

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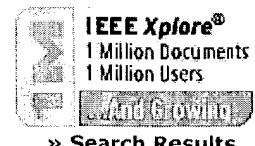
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Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

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- [By Author](#)
- [Basic](#)
- [Advanced](#)

Member Services

- [Join IEEE](#)
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- [Access the IEEE Enterprise File Cabinet](#)

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[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC](#)
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Establish IEEE Web Account
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And

canard In: All Fields

And

spin In: All Fields

Search Clear

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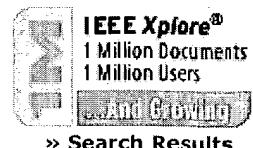
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

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- By Author
- Basic
- Advanced

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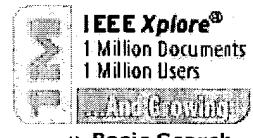
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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- Access the IEEE Enterprise File Cabinet

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- In: Descending order
- List 15 Results per page



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- [Home](#)
- [What Can I Access?](#)
- [Log-out](#)

Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)

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- [Join IEEE](#)
- [Establish IEEE Web Account](#)
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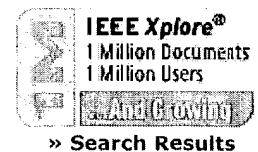
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[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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And

canard In: All Fields

And

counterspin In: All Fields

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Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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Tables of Contents

- Journals & Magazines
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- Standards

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- Basic
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counterspun In: All Fields

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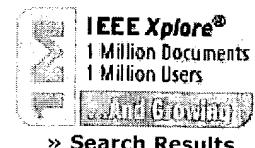
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- In: **Descending** order
- List **15** Results per page



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- Home
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- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

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- By Author
- Basic
- Advanced

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- Join IEEE
- Establish IEEE Web Account
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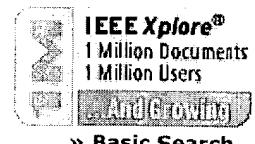
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- Home
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- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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 List Results per page



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- Home
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- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Join IEEE
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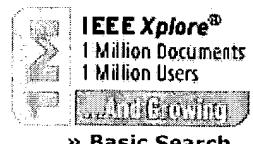
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

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- By Author
- Basic
- Advanced

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Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)

Member Services

- [Join IEEE](#)
- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

IEEE Enterprise

- [Access the IEEE Enterprise File Cabinet](#)

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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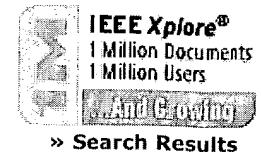
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- [Home](#)
- [What Can I Access?](#)
- [Log-out](#)

Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)

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- [Join IEEE](#)
- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

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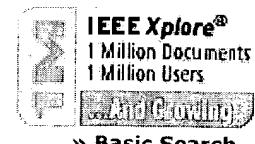
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- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

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- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

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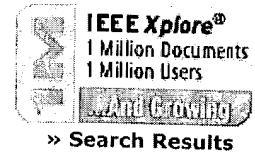
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**Welcome to IEEE Xplore®**

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

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